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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/885,627	06/20/2001	Chris P. Calkins	A019	4531

23623 7590 06/27/2003

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[REDACTED] EXAMINER

PAK, SUNG H

ART UNIT	PAPER NUMBER
	2874

DATE MAILED: 06/27/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

<b>Office Action Summary</b>	Application No.	Applicant(s)
	09/885,627	CALKINS ET AL.
	Examiner Sung H. Pak	Art Unit 2874

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

**Status**

- 1) Responsive to communication(s) filed on \_\_\_\_\_.
- 2a) This action is **FINAL**.                    2b) This action is non-final.
- 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

**Disposition of Claims**

- 4) Claim(s) 1-22 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) Claim(s) \_\_\_\_\_ is/are allowed.
- 6) Claim(s) 1-22 is/are rejected.
- 7) Claim(s) \_\_\_\_\_ is/are objected to.
- 8) Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

**Application Papers**

- 9) The specification is objected to by the Examiner.
- 10) The drawing(s) filed on \_\_\_\_\_ is/are: a) accepted or b) objected to by the Examiner.  
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- 11) The proposed drawing correction filed on \_\_\_\_\_ is: a) approved b) disapproved by the Examiner.  
 If approved, corrected drawings are required in reply to this Office action.
- 12) The oath or declaration is objected to by the Examiner.

**Priority under 35 U.S.C. §§ 119 and 120**

- 13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  
 a) All    b) Some \* c) None of:
  1. Certified copies of the priority documents have been received.
  2. Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
  3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.
- 14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).  
 a) The translation of the foreign language provisional application has been received.
- 15) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

**Attachment(s)**

1) <input type="checkbox"/> Notice of References Cited (PTO-892)	4) <input type="checkbox"/> Interview Summary (PTO-413) Paper No(s). _____ .
2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)	5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152)
3) <input checked="" type="checkbox"/> Information Disclosure Statement(s) (PTO-1449) Paper No(s) <u>2</u> .	6) <input type="checkbox"/> Other: _____ .

## DETAILED ACTION

### ***Information Disclosure Statement***

All references submitted in the information disclosure statement have been considered by the examiner. Please refer to PTO-1449 enclosed herewith.

### ***Claim Rejections - 35 USC § 103***

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

Claims 1-22 are rejected under 35 U.S.C. 103(a) as being unpatentable over Mitwalsky et al (US 5,789,302) in view of Doerr (US 6,219,471 B1).

Doerr reference was cited in the information disclosure statement.

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Mitwalsky et al reference discloses a method of dicing a substrate and a structure including all the limitations set forth in the claims, except it does not teach the cutting of the wafer in a curvilinear manner. Specifically Mitwalsky et al reference discloses: providing a wafer comprising integrated circuits ("214", "216" Fig. 2); forming crack stops in the wafer, each crack stops disposed adjacent and parallel to integrated circuits ("250" Fig. 2); cutting the wafer to yield plurality of separated integrated circuits (column 1 lines 61-67).

Regarding claims 3-4, 19-20, Mitwalsky et al reference teaches formation of crack stops by removing portion of the wafer substrates (column 3 lines 6-12).

Regarding claim 12, Mitwalsky et al reference teaches crack stops being composed of hard and soft passivation layers (column 2 lines 60-62).

Regarding claims 5, 10, Mitwalsky et al reference teaches forming crack stops by chemical etching (column 3 lines 19-27).

Regarding claims 16, Mitwalsky et al reference teaches the use of silicon dioxide substrates (column 2 line 53).

On the other hand, Doerr reference teaches cutting the optical device substrates in a curvilinear manner to form curved optical integrated circuits (Fig. 3-4). Doerr explicitly teaches that such a configuration is advantageous over the prior art because it provides for low polarization sensitivity (abstract). Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to modify Mitwalsky et al invention to have optical integrated circuits cut in a curvilinear manner. It would have been desirable to have efficient optical integrated circuit devices.

***Conclusion***

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Abe et al (US 4,610,079), Choo et al (US 6,407,360 B1), and Brintzinger (US 6,495,918 B1) disclose formation of crack stops in silicon wafers.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sung H. Pak whose telephone number is (703) 308-4880. The examiner can normally be reached on Monday - Thursday : 6:30am-5:00pm.

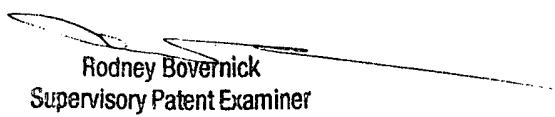
The fax phone numbers for the organization where this application or proceeding is assigned are (703) 308-7724 for regular communications and (703) 308-7724 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.



Sung H. Pak  
Examiner  
Art Unit 2874

sp  
June 20, 2003



Rodney Bovernick  
Supervisory Patent Examiner  
Technology Center 2800